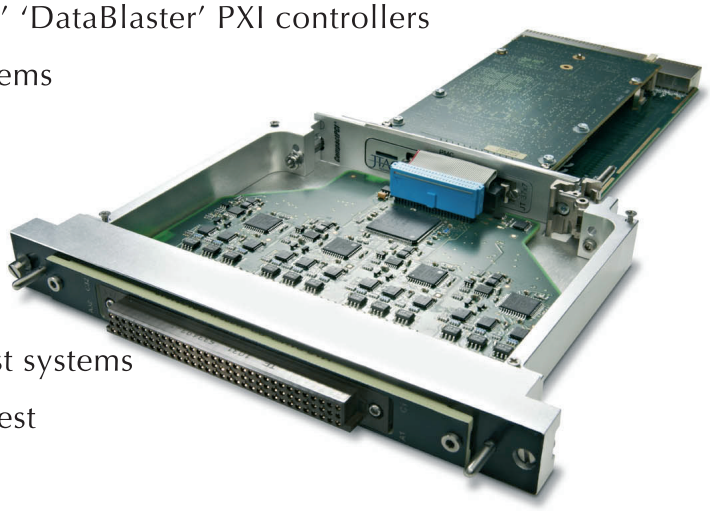
JT 2147/DAK - JTAG/Boundary-scan Interface System

Custom signal-conditioning pod for use with MAC-Panel Scout

- High integrity interface for JTAG Technologies' 'DataBlaster' PXI controllers
- Fits MAC-Panel mass interconnect 'Scout' systems
- DAK- Direct Access Kit form factor
- Provides four JTAG Test Access Ports (TAPs)
- Enables high-speed boundary-scan test & device programming applications
- Ideal for Mil-Aero and Telecoms functional test systems
- Preserves signal integrity right to the point of test



Introduction

The JT 2147/DAK is a signal conditioning module that allows 'perfect world' connections from JTAG Technologies PXI DataBlaster to the Scout's connection system.

Using the same technology as the widely used bench-top QuadPod from JTAG Technologies, the JT 2147/DAK has been specifically designed to locate in the form factor allowed by MAC-Panels 'Direct Access Kits' (DAKs). By using the JT 2147/DAK, test system builders will greatly simplify their wiring task and, at the same time, retain the excellent signal integrity assured by the QuadPod's active interface.

The JT2147/DAK features four independent JTAG Test Access Ports (TAPs) along with 16 user assigned DIO channels. Each TAP can be programmed to operate through a range of voltage levels to suit various logic families.

JTAG/boundary-scan applications prepared using JTAG Technologies ProVision or 'Classic' software tools may be executed on this PXI platform with driver packages that are available for NI LabView, TestStand and LabWindows alongside Geotest ATEasy and a number of generic language compilers (e.g. .NET framework, C++, VisualBasic)

DAK adapters utilize standard MAC Panel series connector modules, providing a wide variety of contact types. The connection between the PXI instrument and receiver module is accomplished using either a passive printed circuit board, active signal condition module (as with the JT 2147/DAK) or flex circuit, with each providing optimum connectivity performance while reducing wiring cost.

Specifications brief

- Incorporates four IEEE Std. 1149.x test access ports
- Supports gang testing or synchronised across all 4 TAPs
- 40 MHz max TCK using internal reference clock
- Features AutoWrite™ for faster flash programming
- Output voltage 1.0V to 3.6V programmable per TAP
- Input threshold 0.5V to 1.8V programmable per TAP
- 16 'static' DIO lines (for relay switching etc..)
- Direct connect to JT 37xx/PXI(e) controllers

Ordering information

Part reference: JT 2147/DAK

Quote request: sales@jtag.com